

covering Electronic Components, Assemblies, Related Materials and Processes

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### Schedule of Scope to Certificate of Approval

**Independent Testing Laboratory** 

IECQ Certificate No.: IECQ-L ULTW 16.0003-03

CB Certificate No.: 20003649 ITL

Schedule Number: IECQ-L ULTW 16.0003-03-S Rev No.: 5 Revision Date: 2022/07/13 Page 1 of 4

### Appendix-1 (20003649 ITL) Schedule of Scope to Certificate of Approval

Description test	Standard
Scanning Electron Microscope (SEM)	T-SEM-3
Transmission Electron Microscope - Electron Energy Loss Spectroscopy (TEM-EELS)	T-TEM-3
Energy Dispersive Spectrometry of X-ray (EDS)	T-SEM-3, T-TEM-3
Focused Ion Beam microscope (FIB)	T-FIB-3
Secondary Ion Mass Spectrometry (SIMS)	T-SIM-3
Atomic Force Microscope (AFM)	T-SIM-3
Spreading Resistance Probe (SRP)	T-SIM-3
Alpha step	T-SIM-3
X-Ray Diffraction (XRD)	T-SIM-3
X-Ray Photoelectron Spectroscopy (XPS)	T-SIM-3
X-Ray	T-EFA-3
Emission Microscopy (EMMI)	T-EFA-3
EMMI-InGaAs	T-EFA-3
Optical Beam Induced Resistance Change (OBIRCH)	T-EFA-3
Conductive atomic force microscopy (C-AFM)	T-EFA-3
Scanning Acoustic Tomography (SAT)	T-EFA-3

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Optical Microscope (OM)	T-OMI-3		
3D Optical Microscope (3D OM)	T-LAB-3		
Optical Profiler (OP)	T-SIM-3		
IC Layout Imaging	T-OMI-3		
Circuitry analysis	T-OMI-3		
Auger	T-SIM-3		
THEMOS	T-EFA-3		
3D X-Ray	T-EFA-3		
Latch-up	JESD78		
Human Body Mode (HBM)	ANSI/ESDA/JEDEC JS-001, ANSI/ESD STM 5.1, JESD22-A114, MIL-STD-883, AEC-Q100-002		
Machine Mode (MM)	ANSI/ESD S5.2, JESD22-A115, AEC-Q100-003		
Charge Device Mode (CDM)	ANSI/ESD SP5.3.2, ANSI/ESD S5.3.1, JESD22-C101, ANSI/ESDA/JEDEC JS-002, AEC-Q100-011,		
ESD Gun	IEC 61000-4-2		
Electrical Overstress (EOS)	IEC 61000-4-5		
Transmission Line Pulse (TLP)	ANSI/ESD STM5.5.1, ANSI/ESD SP5.5.2		
Wire Bonding	T-EFA-3		
IC Package	T-EFA-3		
Pull and shear test	MIL-STD-883 method 2011.9 MIL-STD-883 method 2023.7 AEC-Q100-001, EIA/JESD22-B116, JESD22-B117		
High Temperature Operation Life test (HTOL)	IEC 60068-2-1, JESD22-A108		

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IEC 60068-2-1, JESD22-A108
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JESD22-A104
IEC 60068-2-14/33
JESD22-A106
IEC 60068-2-2, JESD22-A103
IEC 60068-2-1, JESD22-A119
JESD22-A102, JESD22-A118
JESD22-A110
IEC 60068-2-3, JEDEC22 A101
JEDEC22 A101
JESD22-A108
JESD22-A108
JESD22-A101
MIL-STD-750 Method 1037
JESD22-A113
J-STD-020
J-STD-002
IPC-A-610, IPC-A-600
ISTA 2A, IEC 60068-2-32
IEC 60068-2-6/27/29/34/64

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Salt atmosphere street test	JESC	D22-A107, IEC 60068-2-11/52	
Gas corrosion test	IEC (	60068-2-42/43/49/60	
Electro-migration test	IPC ·	TM650 2.6.25	
Conductive resistance test	IPC	9701	

Technical Reviewer of DQS: \_\_\_\_\_ Michael Chou \_\_\_\_\_ Date: 7/13/2022

